


Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/630,949	REED ET AL.	
	Examiner	Art Unit	
	Hiep Nguyen	2816	

ISSUE CLASSIFICATION									
ORIGINAL				CROSS REFERENCE(S)					
CLASS		SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
327		323		361	91.1	91.7	93.9		
INTERNATIONAL CLASSIFICATION				327					
H	O	3	L	5	1	0	0		
HIEP NGUYEN				TUAN T. LAM				Total Claims Allowed: 11	
(Assistant Examiner) (Date) 01.27.05				PRIMARY EXAMINER				O.G. Print Claim(s)	O.G. Print Fig.
Janette Smith 2/3/05				(Primary Examiner) (Date) 2/1/05				1	5
(Legal Instruments Examiner) (Date)									

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant				<input type="checkbox"/> CPA				<input type="checkbox"/> T.D.				<input type="checkbox"/> R.1.47			
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